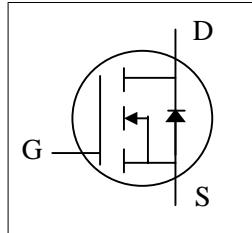


N-CHANNEL ENHANCEMENT MODE POWER MOSFET

PRODUCT SUMMARY

Simple Drive Requirement
Low On-Resistance
Fast Switching Characteristic

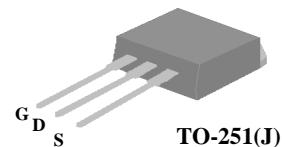
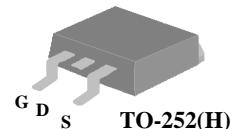


BV_{DSS}	25V
$R_{DS(ON)}$	9mΩ
I_D	62A

DESCRIPTION

The advanced power MOSFETs from Silicon Standard Corp. provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-252 package is universally preferred for all commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters. The through-hole version (SSM72T02GH) are available for low-profile applications.



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	25	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D@T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	62	A
$I_D@T_C=100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	44	A
I_{DM}	Pulsed Drain Current ¹	190	A
$P_D@T_C=25^\circ\text{C}$	Total Power Dissipation	60	W
	Linear Derating Factor	0.4	W/°C
E_{AS}	Single Pulse Avalanche Energy ³	29	mJ
I_{AR}	Avalanche Current	24	A
T_{STG}	Storage Temperature Range	-55 to 175	°C
T_J	Operating Junction Temperature Range	-55 to 175	°C

THERMAL DATA

Symbol	.	Value	Units
R_{thj-c}	Thermal Resistance Junction-case	Max.	°C/W
R_{thj-a}	Thermal Resistance Junction-ambient	Max.	°C/W

ELECTRICAL CHARACTERISTICS

($T_j=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$	25	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_D=1\text{mA}$	-	0.02	-	V/ $^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_D=30\text{A}$	-	8	9	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_D=15\text{A}$	-	11	15	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_D=250\mu\text{A}$	1	-	3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}$, $I_D=30\text{A}$	-	42	-	S
I_{DSS}	Drain-Source Leakage Current ($T_j=25^\circ\text{C}$)	$V_{\text{DS}}=25\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	1	μA
	Drain-Source Leakage Current ($T_j=175^\circ\text{C}$)	$V_{\text{DS}}=20\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	25	μA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}= \pm 20\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_D=30\text{A}$	-	13	21	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=20\text{V}$	-	2.7	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=4.5\text{V}$	-	9	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ²	$V_{\text{DS}}=15\text{V}$	-	8	-	ns
t_r	Rise Time	$I_D=30\text{A}$	-	80	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=3.3\Omega$, $V_{\text{GS}}=10\text{V}$	-	22	-	ns
t_f	Fall Time	$R_D=0.5\Omega$	-	6	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	930	1490	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	250	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	180	-	pF
R_g	Gate Resistance	f=1.0MHz	-	1.1	1.7	Ω

SOURCE-DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_S=30\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	1.3	V
t_{rr}	Reverse Recovery Time ²	$I_S=15\text{A}$, $V_{\text{GS}}=0\text{V}$,	-	26	-	ns
Q_{rr}	Reverse Recovery Charge	$dI/dt=100\text{A}/\mu\text{s}$	-	15	-	nC

Notes:

- 1.Pulse width limited by max. junction temperature.
- 2.Pulse test
- 3.Starting $T_j=25^\circ\text{C}$, $V_{\text{DD}}=25\text{V}$, $L=0.1\text{mH}$, $R_G=25\Omega$, $I_{\text{AS}}=24\text{A}$.

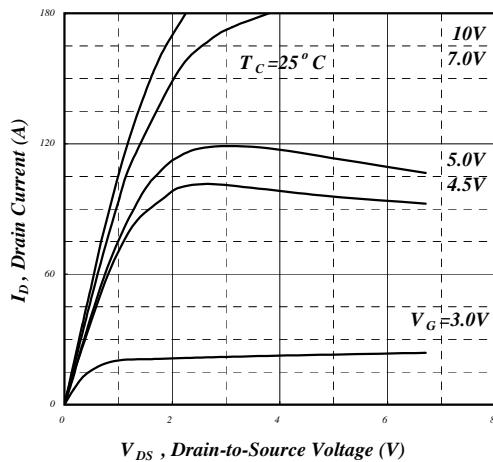


Fig 1. Typical Output Characteristics

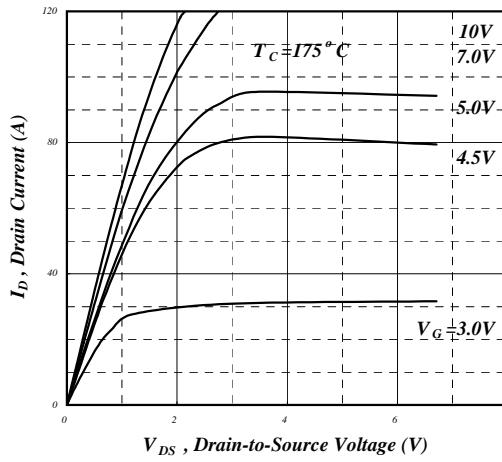


Fig 2. Typical Output Characteristics

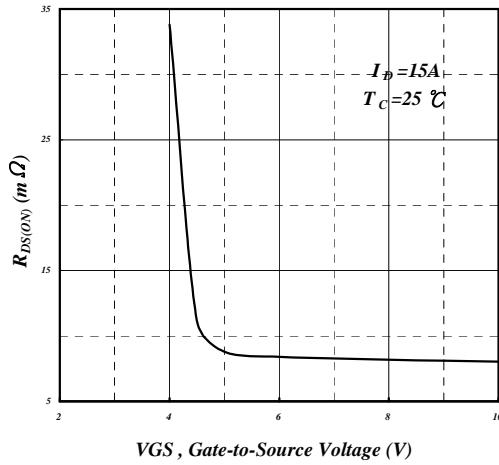


Fig 3. On-Resistance v.s. Gate Voltage

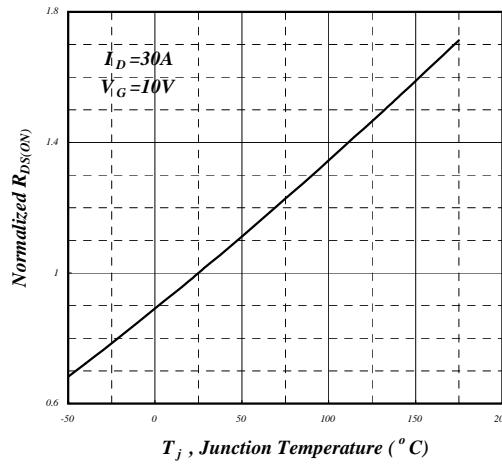


Fig 4. Normalized On-Resistance v.s. Junction Temperature

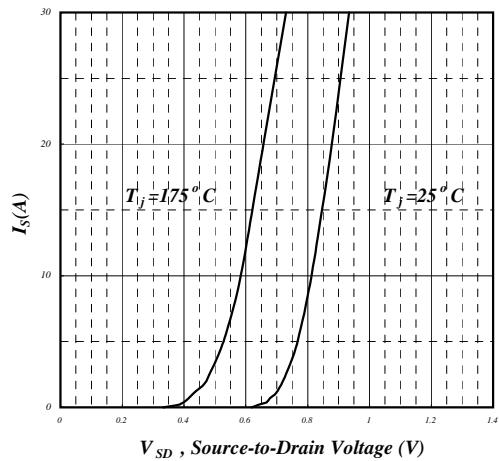


Fig 5. Forward Characteristic of Reverse Diode

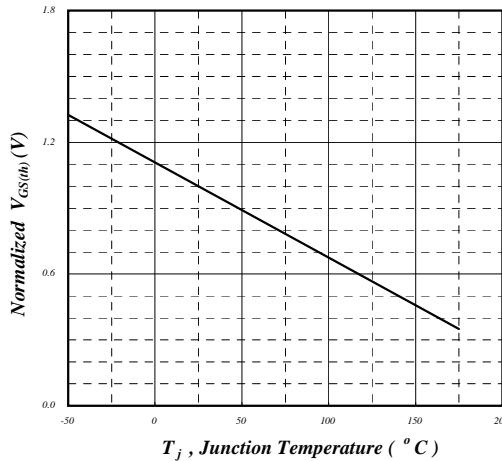


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

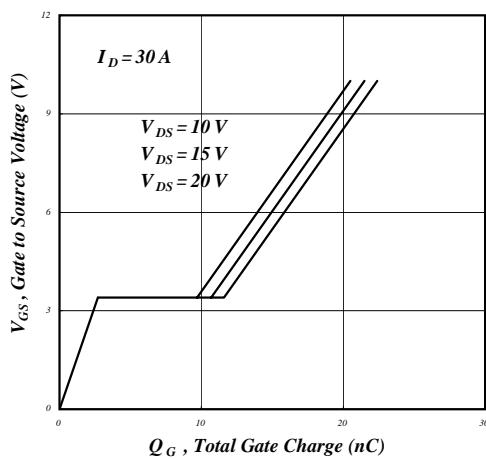


Fig 7. Gate Charge Characteristics

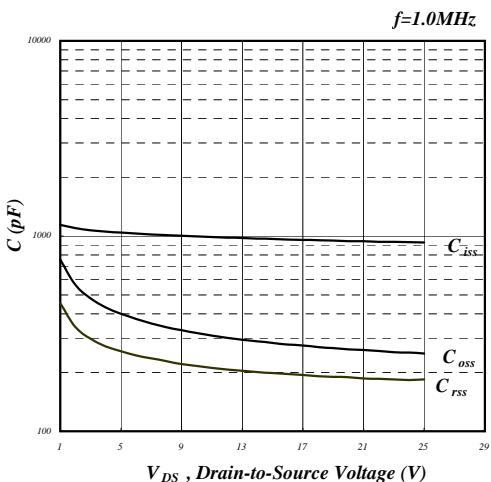


Fig 8. Typical Capacitance Characteristics

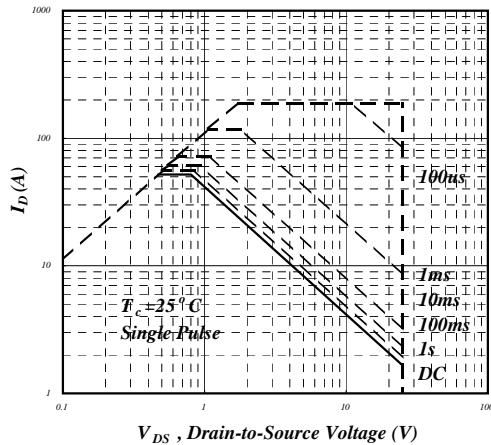


Fig 9. Maximum Safe Operating Area

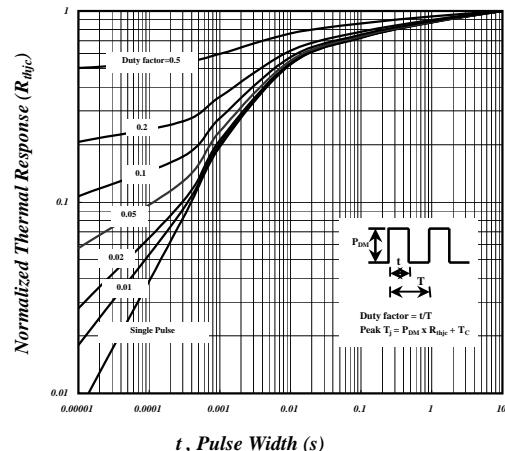


Fig 10. Effective Transient Thermal Impedance

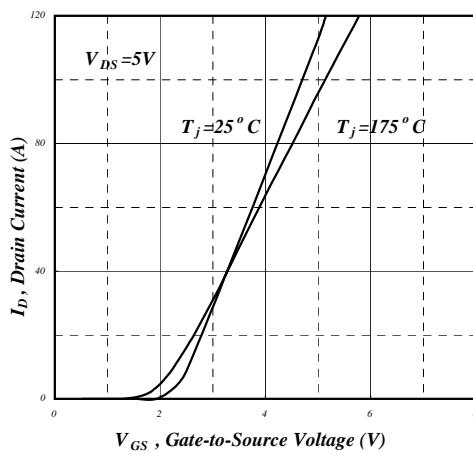


Fig 11. Transfer Characteristics

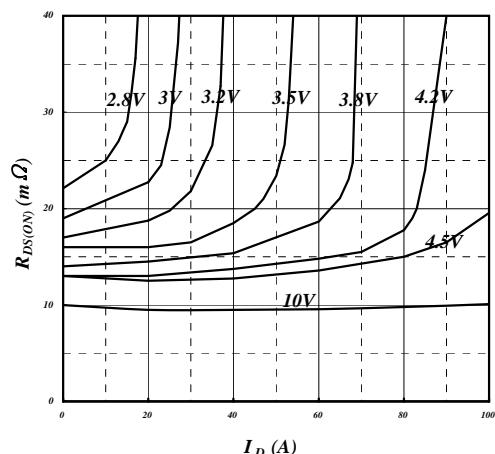


Fig 12. Drain-Source On Resistance

Information furnished by Silicon Standard Corporation is believed to be accurate and reliable. However, Silicon Standard Corporation makes no guarantee or warranty, expressed or implied, as to the reliability, accuracy, timeliness or completeness of such information and assumes no responsibility for its use, or for infringement of any patent or other intellectual property rights of third parties that may result from its use. Silicon Standard reserves the right to make changes as it deems necessary to any products described herein for any reason, including without limitation enhancement in reliability, functionality or design. No license is granted, whether expressly or by implication, in relation to the use of any products described herein or to the use of any information provided herein, under any patent or other intellectual property rights of Silicon Standard Corporation or any third parties.